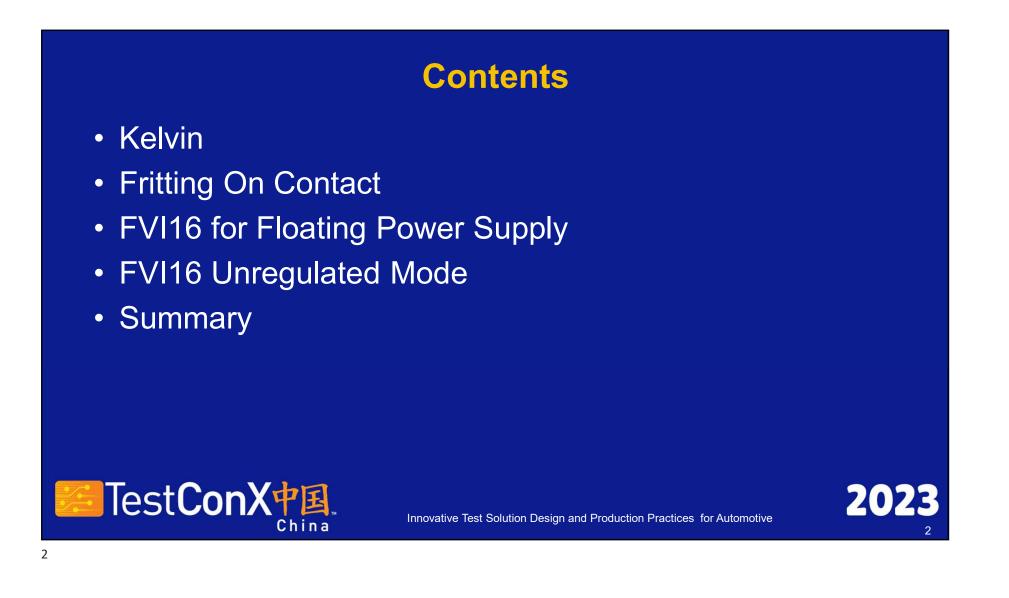
High Precision Contacts & Measurement



TestConX.org

High Precision Contacts & Measurement



Session 2 Presentation 1

TestConX China 2023

High Precision Contacts & Measurement



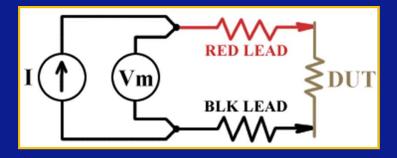
TestConX China Workshop

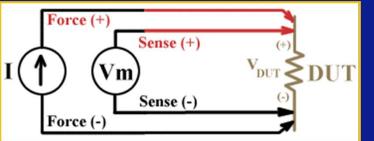
TestConX.org

November 21-23, 2023

High Precision Contacts & Measurement

Kelvin Measurement





A 2-wire measurement really measures the DUT resistance plus the meter lead resistance

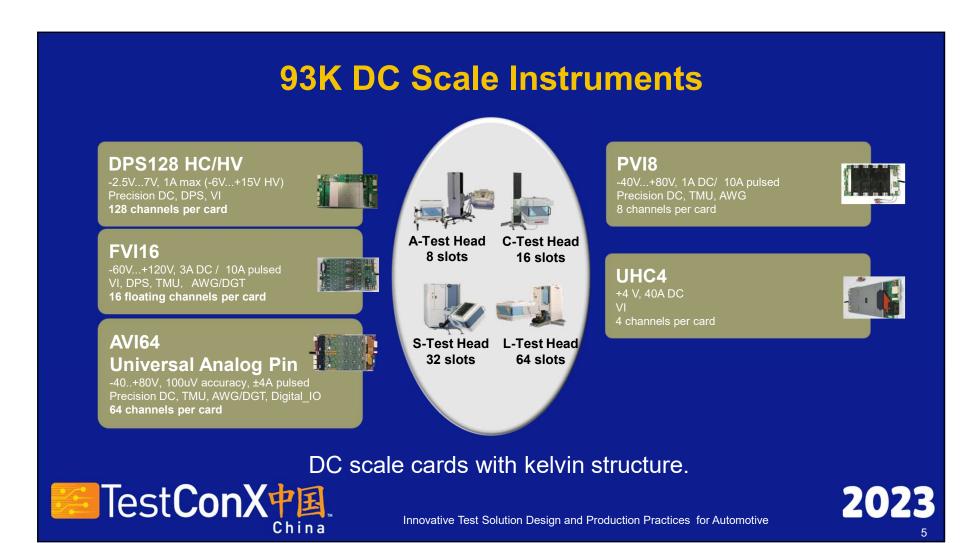
A 4-wire measurement gives you control of where the voltmeter connects -Called Kelvin Measurement

All voltage drops on the line and connection resistance must be compensated by the regulation loop. Therefore, the sense lines are connected at DUT pins directly.

Innovative Test Solution Design and Production Practices for Automotive

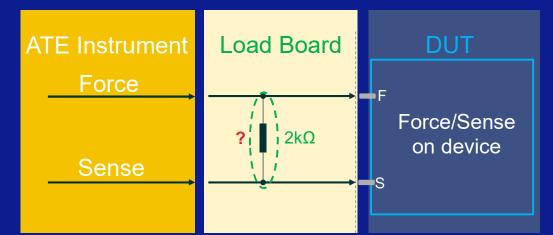


TestConX中国



High Precision Contacts & Measurement

Soft Kelvin Benefits and Considerations



Why do we need the kohm resistor between F/S on load board? When the force and sense present on device, we may damage device in case of abnormal F/S connection. The resistor was used for "soft kelvin".

Do we need the resistor when we use 93K DC instruments in production?

Innovative Test Solution Design and Production Practices for Automotive



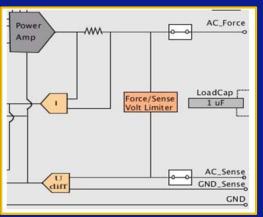
6

TestConX中国

High Precision Contacts & Measurement

Soft Kelvin Benefits and Considerations

DPS128

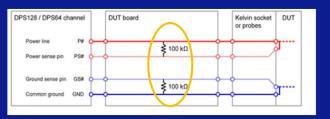


TestConX中国

From cookbook:

- ✓ DPS128 does not implement a local sensing safety circuit, but implements a so-called "force / sense voltage limiter" block. This block guarantees a not to be violated maximum distance between force and force-sense and also acts as a safety feature to prevent unpredictable DPS states.
- ✓ For standard force operation the "force / sense voltage limiter" works in a way that it will tie up the sense to the force, as soon as the there is a voltage difference greater than 1 V.

Recommendations, Add 100 kOhm force to sense bypass resistors on the DUT board to protect against open loop.

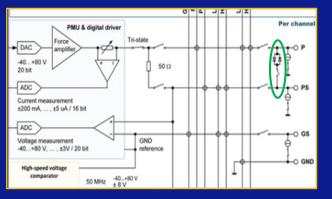


Innovative Test Solution Design and Production Practices for Automotive

High Precision Contacts & Measurement

Soft Kelvin Benefits and Considerations





- ✓ Each AVI64 channel features a <u>switchable clamp circuitry</u> between the P# pogo pin and the PS# pogo pin. This clamp circuitry limits the voltage difference between the two pins for abnormal operating conditions.
- ✓ An abnormal operating condition is for example an open sense connection on the DUT board if the Kelvin connection scheme is used. The closed FS clamp limits the voltage increase on the force line to about 2 V in this case.

Recommendations,

We recommend connecting the two pins **directly** at the DUT so that the digital closed loop control is able to compensate the voltage drop on the P# line.

TestConX+B

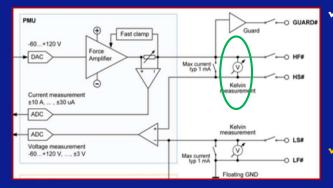
Innovative Test Solution Design and Production Practices for Automotive



High Precision Contacts & Measurement

Soft Kelvin Benefits and Considerations

FVI16



- ✓ Automatic disconnect for weak force to sense connection. To protect probe card needles and test sockets, the VI source output gets automatically disconnected in case a weak force to sense connection leads to a Kelvin voltage drop exceeding the programmed threshold voltage and the VI is set to the 3 A or 10 A range.
- ✓ Disadvantage:

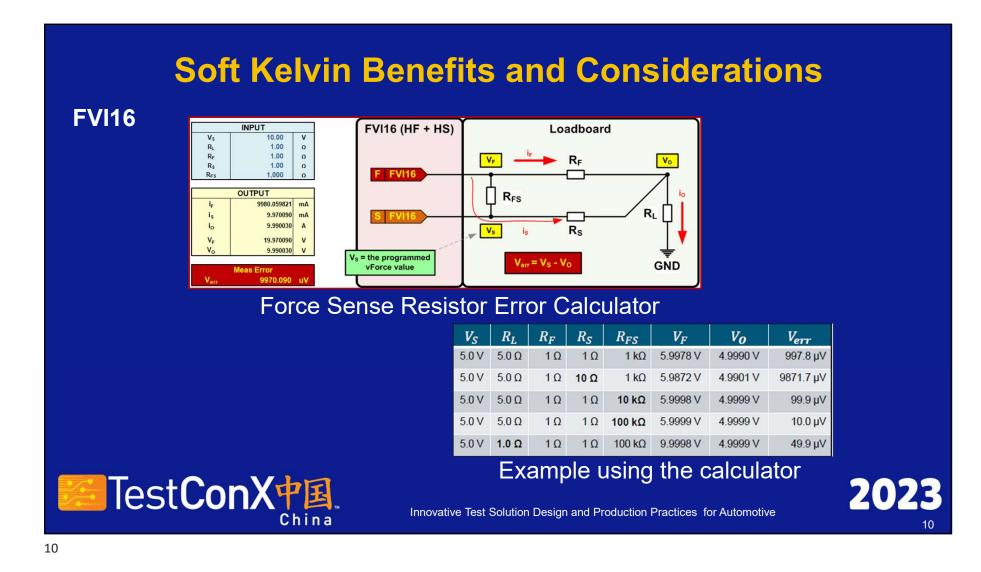
300mA range is excluded from automatic disconnect

Recommendations, We recommend a F/S resistor is optional. Generally, recommend a F/S resistor of at $\geq 10k\Omega$ for the FVI16.

TestConX

Innovative Test Solution Design and Production Practices for Automotive

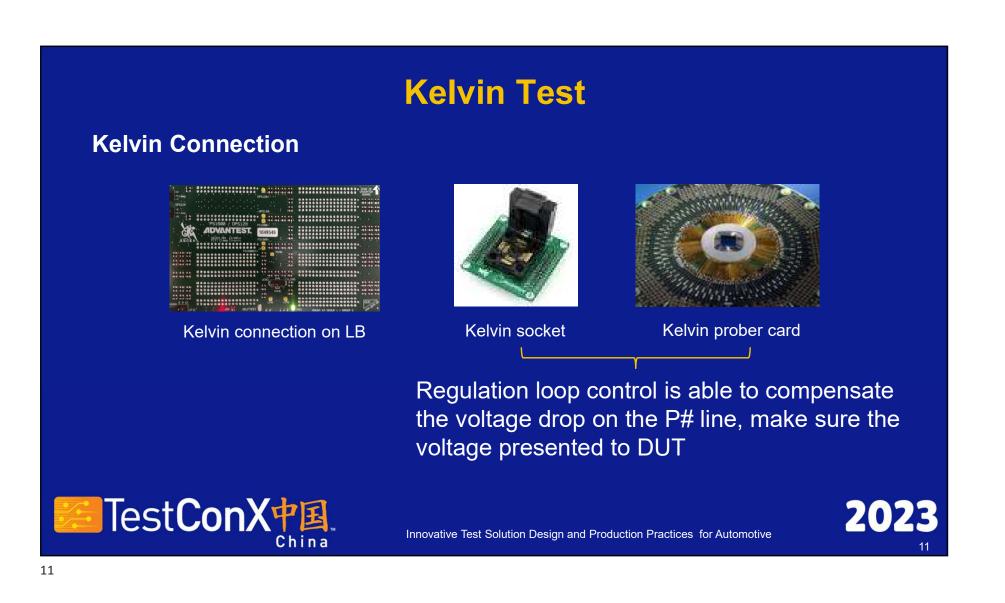


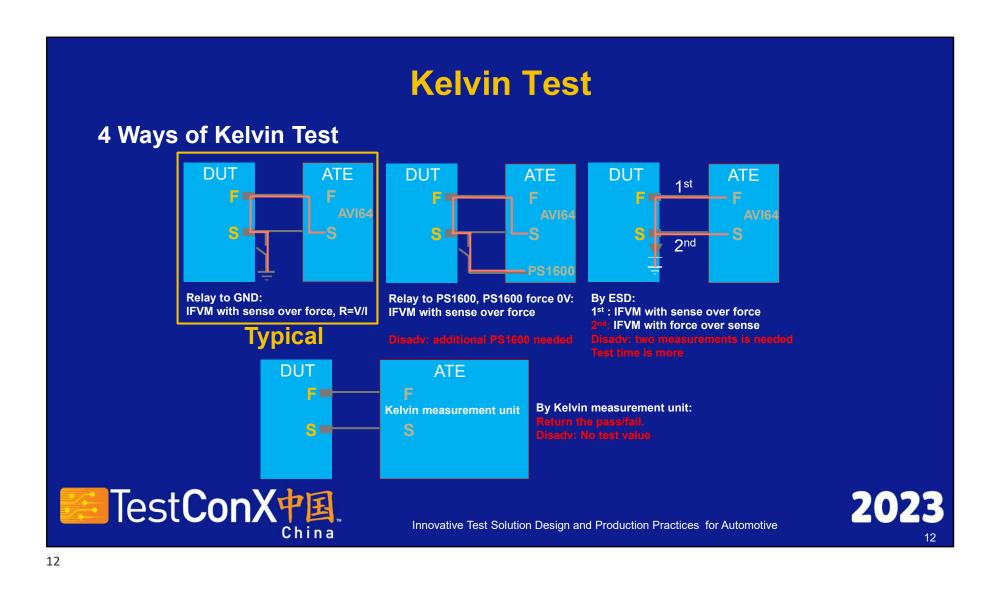


Session 2 Presentation 1

TestConX China 2023

High Precision Contacts & Measurement





Session 2 Presentation 1

TestConX China 2023

High Precision Contacts & Measurement



TestConX China Workshop

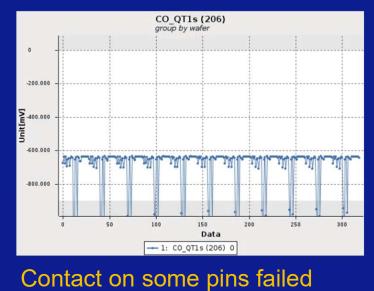
TestConX.org

November 21-23, 2023

High Precision Contacts & Measurement

Background

When the prober card was idle for a long time(days) and then used for production, we will encounter the contact problem. Two prober cards both have same behavior.



China

0 500.000 -1000.00 -1500.00 -1500.00 -1500.00 -1500.00 -1500.00 -1500.00 -1500.00 -1500.00 -1500.00 -1500.00 -1500.00 -1500.00 -11: CO_ENA (306) 0

CO ENA (306)

group by wafer

Contact on some pins pass but outliers

Innovative Test Solution Design and Production Practices for Automotive

14

TestConX中国

High Precision Contacts & Measurement

Some Trials and Significant Improvements

- 1. LB check passing and checked the inside of prober card, no significant findings;
- 2. Did needle alignment, no help;
- 3. Cleaned prober tips and adjusted over drive, no help;
- 4. Switched to another tester and did calibration, no help;
- 5. Debugged the test method, no help;

A significant trial as below improved the contact.

Increase the current to -5 mA and then decrease to -200uA, improved the stability of contact.



Innovative Test Solution Design and Production Practices for Automotive

-200 u

202

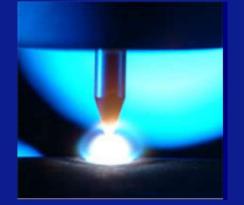
DUT

High Precision Contacts & Measurement

Fritting Theory

Theory of electric contact:

two conductors in mechanical contact, separated by thin insulating layer (e.g., probe needle on Al-pad separated by layer of native oxide)



Fritting Theory:

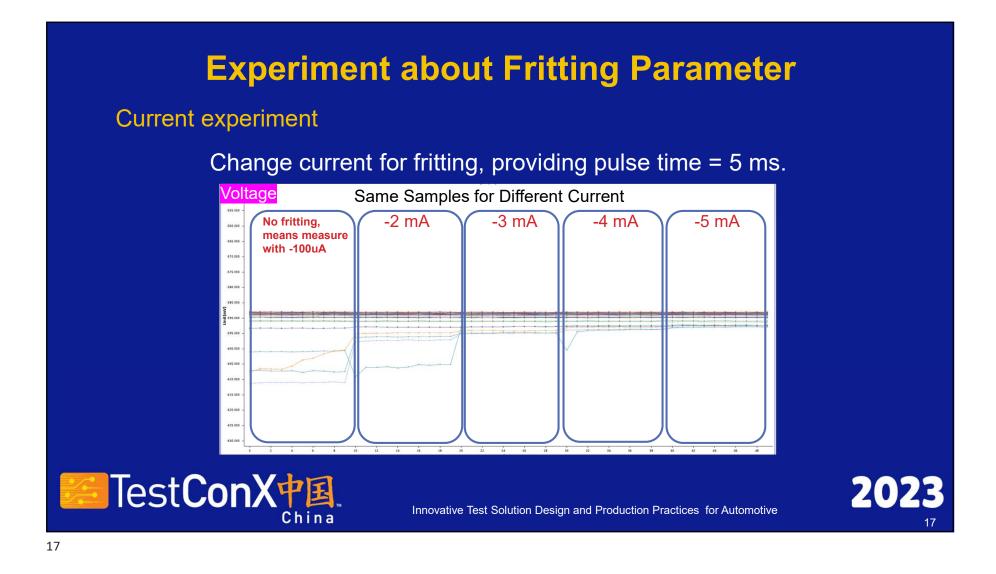
- Fritting is used for the electric contact.
- The higher current is supposed to do a kind of fritting.
- Certain pulse time with the higher current is sufficient.



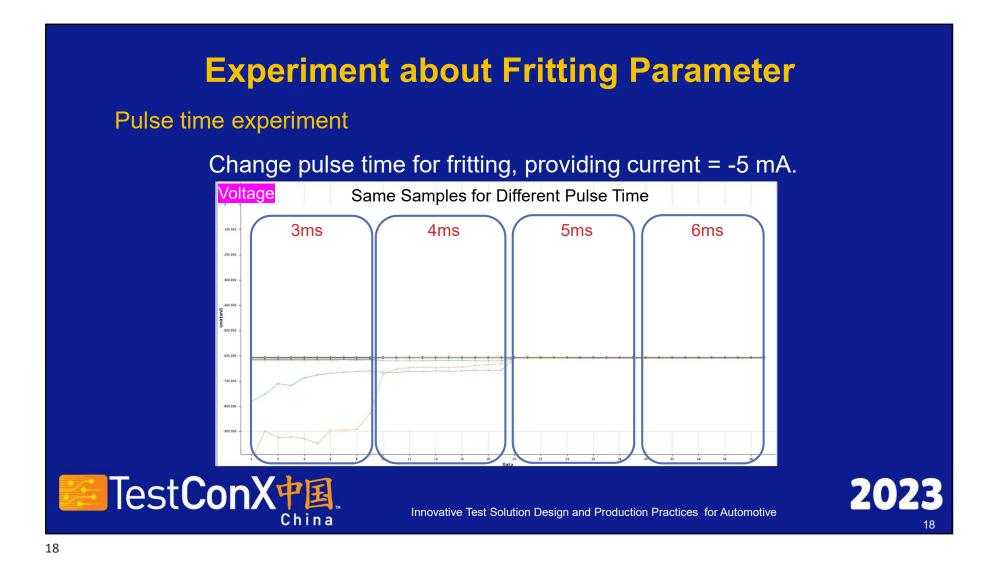
Innovative Test Solution Design and Production Practices for Automotive



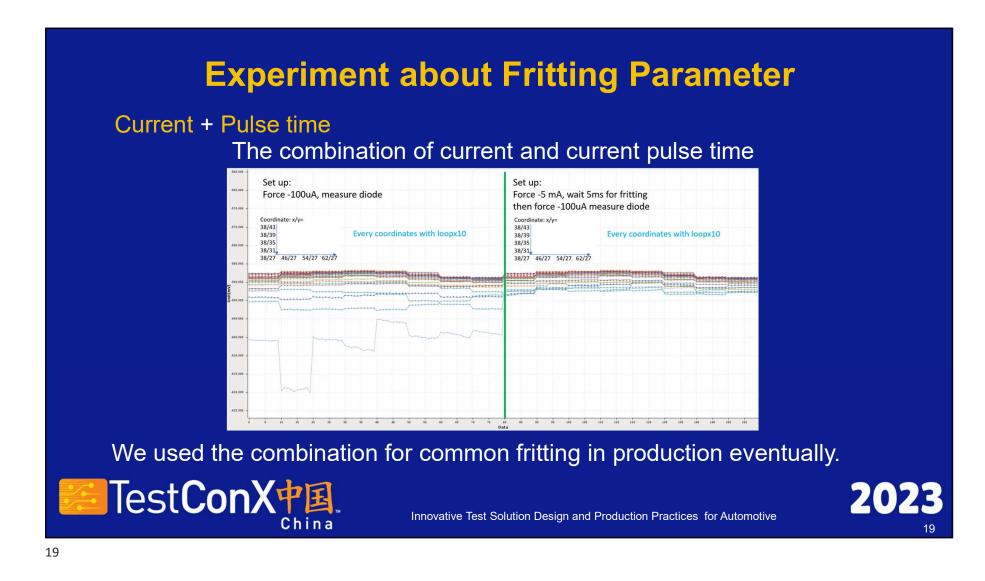
High Precision Contacts & Measurement



High Precision Contacts & Measurement



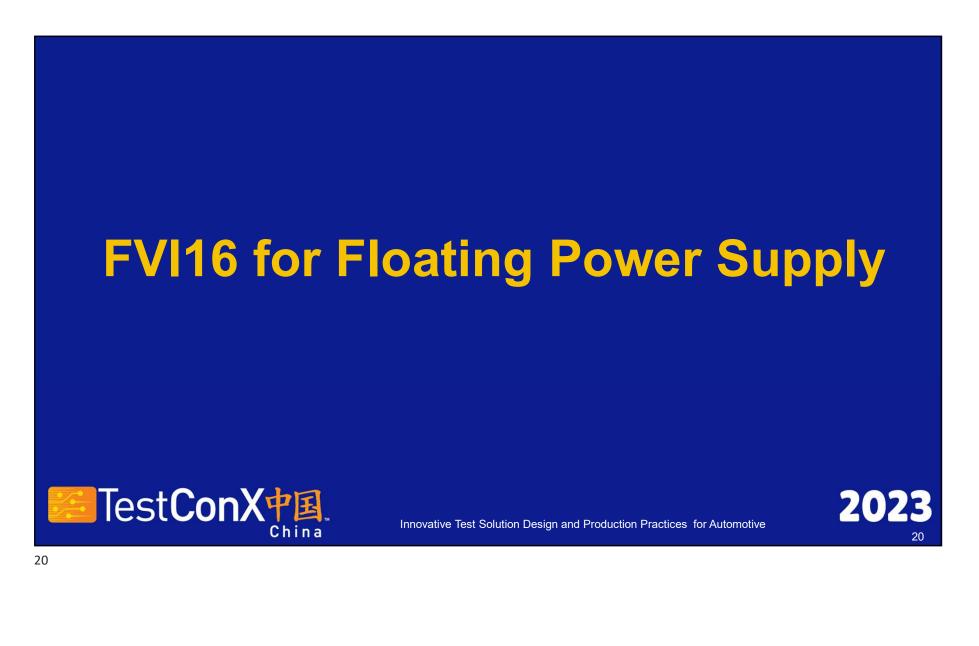
High Precision Contacts & Measurement

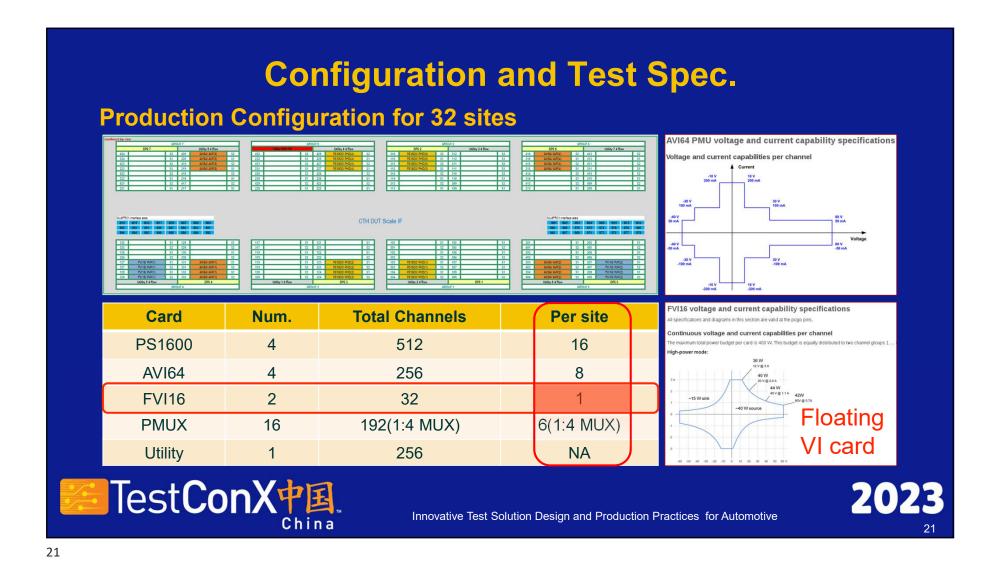


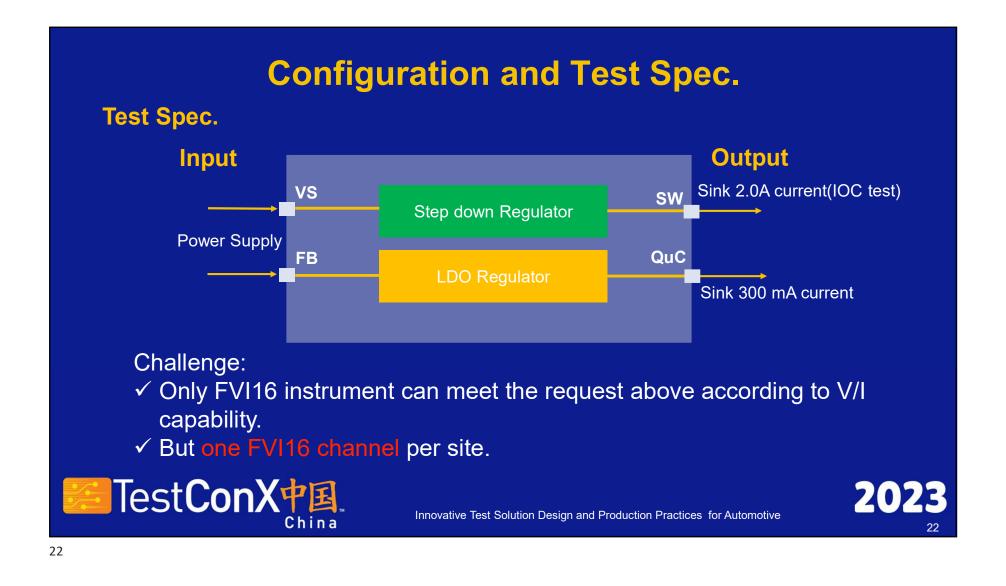
Session 2 Presentation 1

TestConX China 2023

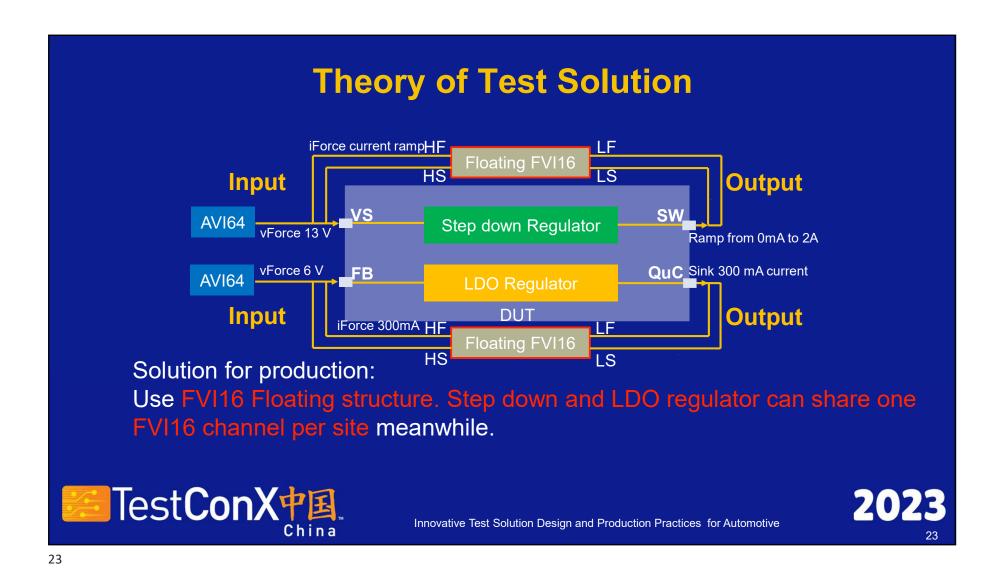
High Precision Contacts & Measurement







High Precision Contacts & Measurement



Session 2 Presentation 1

TestConX China 2023

High Precision Contacts & Measurement



TestConX China Workshop

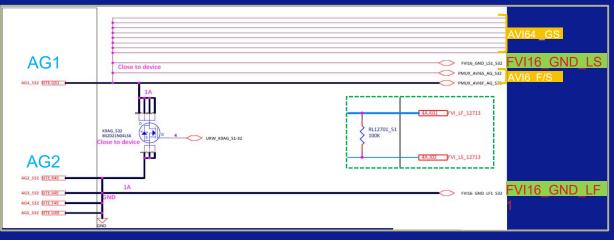
TestConX.org

November 21-23, 2023

High Precision Contacts & Measurement

Background

AGx is device ground and pads above are presented on silicon. Test plan request the kelvin test between AG1 and AG2 inside silicon.



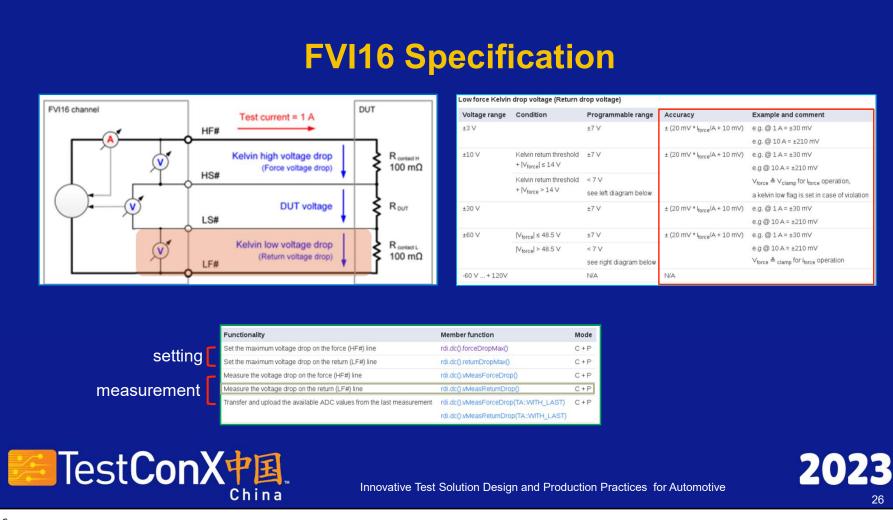
LB design bug:

TestConX中国

If the kelvin between AG1 and AG2 is defective, we would not use FVI16 and AVI64 regulated mode to test the kelvin.

Innovative Test Solution Design and Production Practices for Automotive



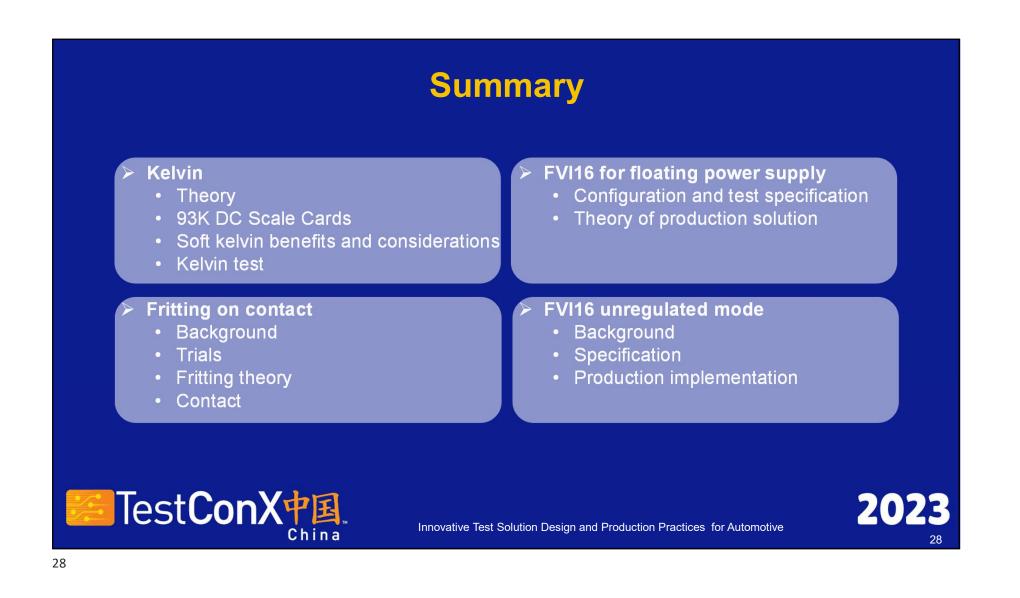


High Precision Contacts & Measurement

•••	Test	Test#	Туре	Low	Upper	Unit	Min	Max	Mean	Sdev	1	Cpk	Cpl	Сри					
		100	P									4.5.45.00	11.7051						
	KSW		Parametric		44.4000			33.9183				4.54588			1.777.1				
	KQCo		Parametric Parametric		19.9000		3.87976	4.66847		9 335		6.82307			(1999)	14	_		
	KQVR KQuC	1.000	Parametric		19.9000		1.5.5.6.5.5.6	2.78969		1100.3076		6.99242 7.77506				esult	S		
	KEBS	0.000	Parametric		44.4000			31.1551			20,2776	6.67348		10000		hen d	lovi	co i	с а(
	KFB45	1.000	Parametric		14.9000			4.42563				5.78756							s yu
	KAG1 2	20202	Parametric	1.0	14.9000		1.25488			8. <i>090</i> .00				1000	10000				
	KPG1S	5105124	Parametric		44,4000	100000	Contraction of Contraction	32,4729	Contractor			5.25318	000000000000000000000000000000000000000	11-2-22					
	KPG1F	119	Parametric	0	14.9000	Ohm	2.38280	2.87175	2.58798	0.1	19715	7.20594	7.20594	34.28	814				
					Test		Test#	Lower	Up	per	Unit	Min	Max		Mean	Sdev	Cpk	Cpl	Cpu
Results when device is				K24FVIQI	JC_OFF	990017	-10.	0000 10	0.0000	uA	-0.05993	66 0.77	7691	0.332379	0.170116	18.9432	20.2458	18.9432	
			K24FVIQU	JC_ON	990018	800	0.000 12	200.00	uA	984.8	33 10	16.96	999.357	4.91012	13.5338	13.5338	13.6211		
				K25FVISV	V1_OFF	990019	-10.	0000 10	0.0000	uA	-0.03477	77 0.52	4626	0.276471	0.107477	30.1568	31.8717	30.1568	
				K25FVISV	V1_ON	990020	800	0.000 12	200.00	uA	957.4	82 108	89.11	995.502	14.9859	4.34858	4.34858	4.54867	
			IS	K9AG_ON	1	990021	800	0.000 12	200.00	uA	995.7	25 100	05.53	1000.34	1.87081	35.5753	35.6949	35.5753	
	defe	efective			K9AG_OF	F	990022	90.	0000 1	10.000	kOhm	95.25	55 97.	.1273	96.4020	0.423854	5.03475	5.03475	10.6939
	ucic				K1VSTOF	F	990023	-10.	0000 10	0.0000	uA	-0.8738	86 1.7	2705	0.525030	0.472882	6.67888	7.41907	6.67888
					K1VSTON	1	990024	800	0.000 12	200.00	uA	992.0	30 100	05.37	1000.22	2.03207	32.7716	32.8429	32.7716

27

High Precision Contacts & Measurement



High Precision Contacts & Measurement

COPYRIGHT NOTICE

This multimedia file is copyright © 2023 by TestConX. All rights reserved. It may not be duplicated or distributed in any form without prior written approval.

The content of this presentation is the work and opinion of the author(s) and is reproduced here as presented at the TestConX China 2023 virtual event.

The TestConX China logo and 'TestConX China' are trademarks of TestConX.

www.testconx.org



